

Ansys Sherlock Overview



Ansys Sherlock Automated Design Analysis software revolutionized electronics design and reliability by empowering designers to simulate real-world conditions and accurately model printed circuit boards (PCBs) and assemblies to predict product failure early in the design process.

As the only tool that uses a reliability physics approach, **Sherlock** continues to innovate and offer enhancements that allow users to manage complex analyses on circuit boards, components and systems that are required more and more in today's electronics products. With **Sherlock** you will:



Make better design decisions in less time



Take the guesswork out of your what-if analyses



Save development and validation time



Identify potential failures more efficiently and effectively

/ Libraries – Embedded Databases Easily Expanded by Users

Parts Library - Electronic parts. Tracks manufacturer, part number, technology type, electrical ratings, temperature ratings and packaging information.

Packages Library - Includes package types for semiconductor and discrete and passive electronic parts. Includes BGAs, QFNs, SOIC, QFP, EIA case sizes, axial, radial, etc.

Materials Library - Electronic materials, including encapsulants, underfills, thermal interface materials, staking compounds, conformal coatings and potting materials.

Laminates Library - Approximately 800 laminate materials from 24 different manufacturers. Includes CEM1, FR4, BT, CE, polyimide, high-temperature and flex.

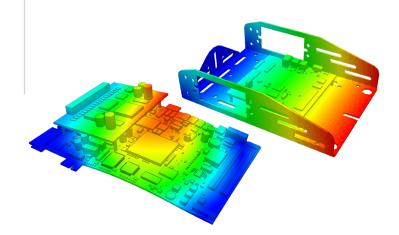
Solders Library - Includes nine solder materials, including SnPb, SAC305, SN100C, 90Pb10Sn, Innolot*, MaxRel*, SACm*, 90iSC* (*available upon request) and M794.

Glass Style Library - Approximately 100 glass styles common to the PCB industry.

/ Sherlock is Your Solution

No matter what your role is in the product development cycle – mechanical analysis, design engineering, product manufacturing and testing or reliability engineering, Sherlock can solve your design challenges.

- Translates ECAD to CAE files
- Predicts product failure
- Designs for manufacturability
- Optimizes the design process
- Analyzes failure mode effects





CAPABILITIES

| FLEXURE/BENDING | Determines if any post-soldering processes could induce excessive flexure that would cause component cracking, pad cratering or solder fracture. |
|--------------------------------------|---|
| CONFORMAL COATING/ POTTING | Allows the user to evaluate the effect of staking compounds, underfills, conformal coatings and potting materials on the reliability of electronic hardware. |
| CAE INTERFACE | Import to and export from finite element analysis (FEA) solvers. |
| THERMAL DERATING | Flags devices being used outside of the specified operation or storage temperature range. |
| TRACE MODELING | Allows the user to explicitly model all PCB features over the entire circuit board or in a particular region. Can be exported for current density, thermal or structural analysis. |
| CERAMIC CAPACITOR WEAROUT | Predicts time to failure for ceramic capacitors (MLCC). |
| ELECTROLYTIC CAPACITOR WEAROUT | Predicts time to failure for aluminum liquid electrolytic capacitors. |
| INTEGRATED CIRCUIT WEAROUT | Predicts failure rate and end of life of integrated circuits using degradation algorithms for electromigration, time-dependent dielectric breakdown, hot carrier injection and negative bias temperature instability. |
| HEATSINK EDITOR | Create pin- and fin-based heatsinks using fill-in fields and drop-down menus and attach them to components or PCBs. |
| DFMEA | Allows the user to semi-automate the creation of a component-level DFMEA. Can be exported into any form/spreadsheet, including SAE J1739. |
| SOLDER FATIGUE 1D, BOARD-LEVEL | Predicts solder fatigue reliability under thermomechanical and mechanical environments for all electronic parts (die attach, BGA, QFN, TSOP, chip resistor, through hole, etc.). |
| SOLDER FATIGUE, 3D, SYSTEM-LEVEL | Incorporates the effect of system-level mechanical elements (chassis, module, housing, connectors, etc.) on solder fatigue analysis. |
| SHOCK AND VIBRATION ANALYSIS | Predicts the natural frequency, displacement, strain and reliability under shock and vibration over a range of temperatures (-55 C to 125 C). |
| PLATED THROUGH-HOLE (PTH) FATIGUE | Predicts fatigue of plated through holes/vias in circuit boards using IPC TR-579 calculations. |
| CONDUCTIVE ANODIC FILAMENT (CAF) | Sherlock benchmarks the printed board design and quality processes to industry best practices to identify risk of CAF failures. |
| PCB/BGA SUBSTRATE STACKUP | Captures stackup from output files (Gerber, ODB++, IPC-2581). Automatically calculates weight, density and in-plane and out-of-plane modulus, coefficient of thermal expansion and thermal conductivity. |
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